

## **BAB V**

### **KESIMPULAN DAN SARAN**

#### **5.1 KESIMPULAN**

Setelah menyelesaikan perancangan, pembuatan, pengukuran dan pengujian alat yang dibuat, dapat ditarik kesimpulan:

- Rangkaian Non Inverting telah bekerja dengan baik
- Rangkaian ADC 8 bit yang digunakan telah bekerja dengan baik
- Rangkaian Penyearah Gelombang Penuh telah bekerja dengan baik

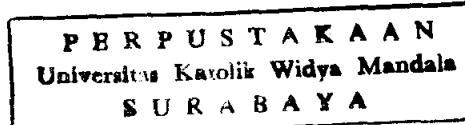
Oleh karena itu secara keseluruhan KWH Meter Digital telah bekerja dengan baik dengan tingkat kesalahan 3.601%

#### **5.2 SARAN**

Untuk mendapatkan hasil perbandingan data yang baik, maka hal-hal yang dapat dipakai guna penyempurnaannya adalah:

Pengesetan MCB yang baik dan benar sehingga menghasilkan hasil yang lebih presisi (batas pemakaian beban).

Mengadakan pengukuran dan pengujian yang lebih sempurna dan teliti.



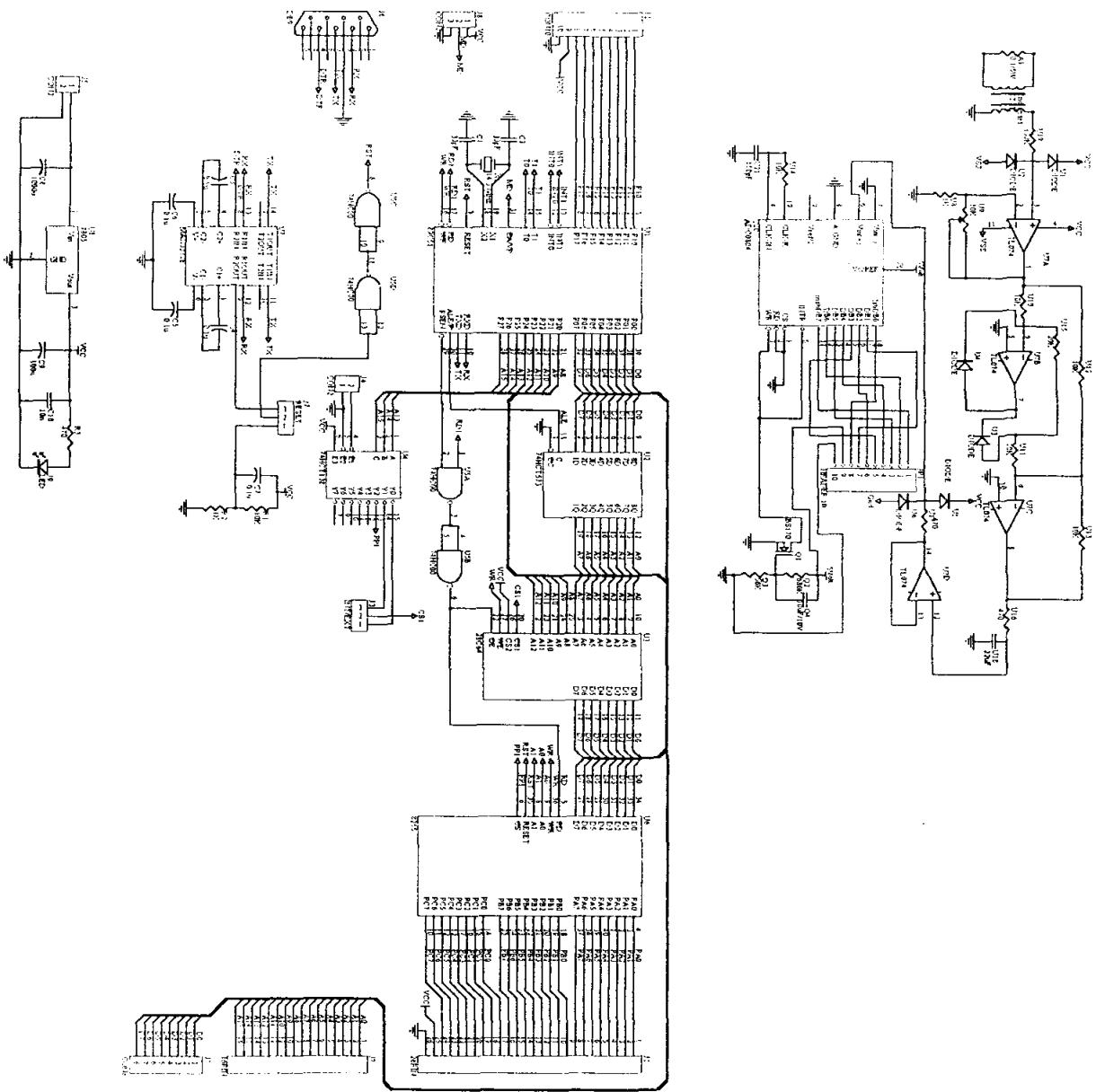
**DAFTAR JUSETKA**

## **DAFTAR PUSTAKA**

1. Floyd ,"*Basic Operational Amplifiers and Linear Integrated Circuit*", New York, 1994
2. Hall, Douglas V,"*Microprocessors and Interfacing Programming and Hardware*", McGraw-Hill, Singapore, 1993.
3. Robert F. Coughlin & Frederick F. Driscoll, "*Penguat Operasional dan Rangkain Terpadu Linier*", Penerbit Erlangga, 1985
4. .....*Down Load Atmel*
5. .....*LCD User Manual*
6. .....*MSC-51 Architecture*
7. .....*National Data Acquisition Databook*, USA, 1995

**LAMPIRAN**

## LAMPIRAN 1



-----  
PERENCANAAN DAN PEMBUATAN ALAT UKUR  
KWH METER DIGITAL  
UNIKA WIDYA MANDALA  
SURABAYA

-----

PA	EQU	4000H	
PB	EQU	4001H	
PC	EQU	4002H	
PCW	EQU	4003H	
CW	EQU	80H	
COUNT	EQU	08H	
TEMP1	EQU	09H	
TEMP2	EQU	0AH	
TEMP3	EQU	0BH	
TEMP4	EQU	0CH	
IN1	EQU	0DH	
IN2	EQU	0EH	
IN3	EQU	0FH	
IN4	EQU	10H	
VAR6	EQU	11H	;VARIABEL 64 BIT
VAR7	EQU	12H	
VAR8	EQU	13H	
VAR9	EQU	14H	
VAR10	EQU	15H	
VAR11	EQU	16H	
VAR12	EQU	17H	;MSB 64 BIT
VAR1	EQU	18H	;LSB 32 BIT
VAR2	EQU	19H	
VAR3	EQU	1AH	
VAR4	EQU	1BH	;MSB 32 BIT
VAR5	DATA	21H	;LSB 64 BIT
WATT1	EQU	1CH	
WATT2	EQU	1DH	
WATT3	EQU	1EH	
WATT4	EQU	1FH	
KWH1	EQU	30H	
KWH2	EQU	31H	
KWH3	EQU	32H	
KWH4	EQU	33H	
UANG1	EQU	34H	
UANG2	EQU	35H	
UANG3	EQU	36H	
UANG4	EQU	37H	
WAKTU1	EQU	38H	

```
WAKTU2 EQU 39H
CURSOR EQU 3AH

ORG 2000H

START AJMP MULAI

        ORG 200BH
;-----;
;    INTERRUPT TIMER0
;-----;

        AJMP TIMER0

        ORG 2100H
;-----;
;    ROUTINE TIMER0
;-----;

TIMER0      DJNZ R4,ESCTR0
            MOV  R4,#48
            DJNZ R5,ESCTR0
            MOV  R5,#100
            INC  WAKTU1
ESCTR0      RETI

;-----;
;    DELAY
;-----;

DELAY       MOV  R7,#0FFH
DEL1        MOV  R6,#0FFH
            DJNZ R6,$
            DJNZ R7,DEL1
            RET

;-----;
;    DELAY LCD
;-----;

DEL_LCD     MOV  R7,#1
DEL2        MOV  R6,#250
            DJNZ R6,$
            DJNZ R7,DEL2
            RET

;-----;
;    INISIALISASI
;-----;

INIT        MOV  WATT1,#0
```

```

        MOV  WATT2,#0
        MOV  WATT3,#0
        MOV  WATT4,#0
        MOV  KWH1,#0
        MOV  KWH2,#0
        MOV  KWH3,#0
        MOV  KWH4,#0
        MOV  UANG1,#0
        MOV  UANG2,#0
        MOV  UANG3,#0
        MOV  UANG4,#0
        MOV  R4,#48
        MOV  R5,#40
        MOV  IE,#82H      ;INTERRUPT TIMER0

ENABLE
        MOV  TMOD,#02H      ;TIMER0 MODE 2
        MOV  TL0,#64
        MOV  TH0,#64
        MOV  WAKTU2,#0
        MOV  WAKTU1,#0

mode2
        MOV  TMOD,#00100010B   ;T1 mode2, T0
        MOV  TL1,#0FAH          ;T1 mode2 generate

BR=9600 Bps
        MOV  TH1,#0FAH
        MOV  TCON,#01000000B    ;T1 on,T0 off
        MOV  SCON,#01010000B    ;Mode1,REN
        MOV  PCON,#80H          ;SMOD=0

        SETB TR0
        RET

-----
;      SUBROUTINE LCD
-----
SUB_LCD      MOV  DPTR,#PA
              MOVX @DPTR,A
              MOV  A,#02H      ;ENABLE HIGH
              MOV  DPTR,#PC
              MOVX @DPTR,A
              ACALL DEL_LCD
              MOV  A,#0      ;ENABLE LOW
              MOVX @DPTR,A
              RET

```

```

;-----[LCD]-----;
;      LCD
;-----[LCD]-----;

LCD      MOV A,#3FH      ;RESETLCD
         ACALL SUB_LCD
         MOV A,#0CH      ;DISPLAY ON/OFF
         ACALL SUB_LCD
         MOV A,#06H      ;DATA ENTRY
         ACALL SUB_LCD
         MOV A,#01H      ;DISPLAY CLEAR
         ACALL SUB_LCD
         MOV A,#80H      ;DISPLAY LINE1 (LINE2=C0);
         ACALL SUB_LCD
         RET

;-----[PEMBAGIAN]-----;
;      PEMBAGIAN
;-----[PEMBAGIAN]-----;

BAGI     MOV A,R0
         PUSH A
         MOV A,R1
         PUSH A
         MOV A,R2
         PUSH A
         MOV IN1,VAR1
         MOV IN2,VAR2
         MOV IN3,VAR3
         MOV IN4,VAR4
         MOV VAR1,#0
         MOV VAR2,#0
         MOV VAR3,#0
         MOV VAR4,#0
         MOV COUNT,#64
         BAGI1      CLR C
         MOV A,VAR5      ;GESER LSB 64 BIT
         RLC A
         MOV VAR5,A
         MOV R0,#11H      ;ALAMAT VAR6
         MOV R2,#11
         SHIFT      MOV A,@R0      ;GESER KIRI
         RLC A
         MOV @R0,A
         INC R0
         DJNZ R2,SHIFT
         MOV TEMP1,VAR1
         MOV TEMP2,VAR2

```

```

        MOV  TEMP3,VAR3
        MOV  TEMP4,VAR4
        CLR  C          ;PENGURANGAN
        MOV  R0,#18H
        MOV  R1,#0DH
        MOV  R2,#4
KURANG      MOV  A,@R0
              SUBB A,@R1
              MOV  @R0,A
              INC  R0
              INC  R1
              DJNZ R2,KURANG
              JC   CLEAR_VARBIT0 ;CEK APAKAH RESULT

NEGATIVE    SETB VAR5.0
              AJMP CEKCOUNTER
CLEAR_VARBIT0 MOV  VAR1,TEMP1
                MOV  VAR2,TEMP2
                MOV  VAR3,TEMP3
                MOV  VAR4,TEMP4
CEKCOUNTER   DJNZ COUNT,BAGI1
              POP  A
              MOV  R2,A
              POP  A
              MOV  R1,A
              POP  A
              MOV  R0,A
              RET

;-----;
; PERKALIAN
;-----;

```

```

KALI       MOV  IN1,VAR1
              MOV  IN2,VAR2
              MOV  IN3,VAR3
              MOV  IN4,VAR4
              MOV  VAR9,#0
              MOV  VAR10,#0
              MOV  VAR11,#0
              MOV  VAR12,#0
              MOV  VAR1,#0
              MOV  VAR2,#0
              MOV  VAR3,#0
              MOV  VAR4,#0
              MOV  COUNT,#32
KALI1      CLR  C

```

```

JNB  VAR5.0,PASS2      ;APAKAH Q0 = 0 ?
MOV  R0,#18H
MOV  R1,#0DH
MOV  R2,#4
TAMBAH MOV  A,@R0
ADDC A,@R1
MOV  @R0,A
INC  R0
INC  R1
DJNZ R2,TAMBAH
PASS2 MOV  R0,#1BH      ;ALAMAT VAR6
MOV  R2,#4
SHIFTR1 MOV  A,@R0      ;GESER KANAN
RRC  A
MOV  @R0,A
DEC  R0
DJNZ R2,SHIFTR1
MOV  R0,#13H
MOV  R2,#3
SHIFTR2 MOV  A,@R0
RRC  A
MOV  @R0,A
DEC  R0
DJNZ R2,SHIFTR2
MOV  A,VAR5      ;GESER LSB 64 BIT
RRC  A
MOV  VAR5,A
DJNZ COUNT,KALI1    ;APAKAH COUNTER = 0 ?
MOV  VAR12,VAR4
MOV  VAR11,VAR3
MOV  VAR10,VAR2
MOV  VAR9,VAR1
RET

```

```

;-----;
;      PENJUMLAHAN
;-----;
SUM   CLR  C      ;PENJUMLAHAN
      MOV  A,VAR5
      ADDC A,VAR1
      MOV  VAR5,A
      MOV  R0,#11H
      MOV  R1,#19H
      MOV  R2,#3
JUMLAH MOV  A,@R0
        ADDC A,@R1

```

```
        MOV    @R0,A
        INC    R0
        INC    R1
        DJNZ   R2,JUMLAH
        JNC    ESC_SUM
        INC    VAR9
ESC_SUM    RET

;-----
;      PENGURANGAN
;-----
SUB      CLR    C          ;PENGURANGAN
        MOV    A,VAR5
        SUBB   A,VAR1
        MOV    VAR5,A
        MOV    R0,#11H
        MOV    R1,#19H
        MOV    R2,#3
POTONG   MOV    A,@R0
        SUBB   A,@R1
        MOV    @R0,A
        INC    R0
        INC    R1
        DJNZ   R2,POTONG
        JNC    ESC_SUB
        DEC    VAR9
ESC_SUB   RET

;-----
;      ENABLE DISPLAY
;-----
ENA_DIS  MOV    DPTR,#PA
        MOVX  @DPTR,A
        MOV    A,#03H
        MOV    DPTR,#PC
        MOVX  @DPTR,A
        ACALL  DEL_LCD
        MOV    A,#0
        MOV    DPTR,#PC
        MOVX  @DPTR,A
        RET
```

```
-----
;          DISPLAY KWH
-----
DISP_KWH MOV  R3,#9      ;9 CHAR
           MOV  CURSOR,#15
DISP1     MOV  R2,CURSOR   ;POINTER CURSOR
           DEC  CURSOR
           MOV  A,#80H      ;POINTER MULA-MULA BARIS1
           ACALL SUB_LCD
           ACALL SUB_LCD
DISP2     MOV  A,#14H      ;CURSOR BERGESER
           ACALL SUB_LCD
           DJNZ R2,DISP2
           CJNE R3,#6,DISP3
           MOV  A,#2EH
           AJMP DISP4
DISP3     MOV  VAR1,#10
           MOV  VAR2,#0
           MOV  VAR3,#0
           MOV  VAR4,#0
           ACALL BAGI
           MOV  A,#30H
           ORL  A,VAR1      ;TAMPILKAN SISA DIV 10
DISP4     ACALL ENA_DIS
           DJNZ R3,DISP1
           RET
```

```
-----
;          DISPLAY BIAYA
-----
DISP_BIAYA MOV  R3,#9      ;9 KARAKTER
           MOV  CURSOR,#15
DISP5     MOV  R2,CURSOR   ;POINTER CURSOR
           DEC  CURSOR
           MOV  A,#0C0H      ;POINTER MULA-MULA BARIS 2
           ACALL SUB_LCD
           ACALL SUB_LCD
DISP6     MOV  A,#14H      ;CURSOR BERGESER
           ACALL SUB_LCD
           DJNZ R2,DISP6
           CJNE R3,#7,DISP7
           MOV  A,#2EH
           AJMP DISP8
DISP7     MOV  VAR1,#10
           MOV  VAR2,#0
           MOV  VAR3,#0
```

```

        MOV  VAR4,#0
        ACALL BAGI
        MOV  A,#30H
        ORL  A,VAR1      ;TAMPILKAN SISA DIV 10
DISP8    ACALL ENA_DIS
        DJNZ  R3,DISP5
        RET

;-----;
;   SUBROUTINE STRING
;-----;

SUB_STR     MOV  A,#03      ;R/S OFF
            MOV  DPTR,#PC
            MOVX @DPTR,A
            MOV  A,@R0
            MOV  DPTR,#PA
            MOVX @DPTR,A
            ACALL DEL_LCD
            MOV  A,#0H      ;R/S ON
            MOV  DPTR,#PC
            MOVX @DPTR,A
            ACALL DEL_LCD
            INC  R0
            DJNZ  R2,SUB_STR
            RET

;-----;
; TULISAN 'KWH : ' & 'BIAYA : '
;-----;

STRING      MOV  A,#0      ;CONTROL LCD = 0
            MOV  DPTR,#PC
            MOVX @DPTR,A
            ACALL DEL_LCD
            MOV  VAR6,#4BH    ;{K}
            MOV  VAR7,#57H    ;{W}
            MOV  VAR8,#48H    ;{H}
            MOV  VAR9,#20H    ;{ }
            MOV  VAR10,#20H   ;{ }
            MOV  VAR11,#3AH   ;{:}
            MOV  R0,#11H
            MOV  R2,#6
            ACALL SUB_STR
            MOV  A,#0C0H      ;DISPLAY BARIS 2
            ACALL SUB_LCD
            MOV  VAR6,#43H    ;{C}
            MOV  VAR7,#4FH    ;{O}

```

```
        MOV  VAR8,#53H    ;{S}
        MOV  VAR9,#54H    ;{T}
        MOV  VAR10,#20H   ;{ }
        MOV  VAR11,#3AH   ;{:}
        MOV  R0,#11H
        MOV  R2,#6
        ACALL SUB_STR
        RET

;-----;
;      AKTIFKAN ALU 4 BYTE
;-----;
ALU4BYTE MOV  VAR9,#0
          MOV  VAR10,#0
          MOV  VAR11,#0
          MOV  VAR12,#0
          RET

;-----;
;      PERHITUNGAN KWH METER
;-----;
HITWATT  MOV  VAR5,P1
          MOV  VAR6,#0
          MOV  VAR7,#0
          MOV  VAR8,#0
          ACALL ALU4BYTE
          MOV  VAR1,#51
          MOV  VAR2,#0
          MOV  VAR3,#0
          MOV  VAR4,#0
          ACALL KALI
          MOV  VAR1,WATT1
          MOV  VAR2,WATT2
          MOV  VAR3,WATT3
          MOV  VAR4,WATT4
          ACALL SUM
          MOV  WATT1,VAR5
          MOV  WATT2,VAR6
          MOV  WATT3,VAR7
          MOV  WATT4,VAR8
ESCHIT   RET
```

```
;-----  
; PERHITUNGAN KWH METER & UANG  
;  
HITKWH    MOV    VAR5,WATT1  
          MOV    VAR6,WATT2  
          MOV    VAR7,WATT3  
          MOV    VAR8,WATT4  
          MOV    VAR1,#36  
          MOV    VAR2,#0  
          MOV    VAR3,#0  
          MOV    VAR4,#0  
          ACALL  ALU4BYTE  
          ACALL  BAGI           ;DIBAGI 36  
          MOV    VAR1,#232  
          MOV    VAR2,#3  
          MOV    VAR3,#0  
          MOV    VAR4,#0  
          ACALL  ALU4BYTE  
          ACALL  BAGI           ;DIBAGI 1000  
          MOV    WATT1,VAR1  
          MOV    WATT2,VAR2  
          MOV    WATT3,VAR3  
          MOV    WATT4,VAR4  
          MOV    VAR1,KWH1  
          MOV    VAR2,KWH2  
          MOV    VAR3,KWH3  
          MOV    VAR4,KWH4  
          ACALL  SUM  
          MOV    KWH1,VAR5  
          MOV    KWH2,VAR6  
          MOV    KWH3,VAR7  
          MOV    KWH4,VAR8  
          MOV    VAR1,#9  
          MOV    VAR2,#0  
          MOV    VAR3,#0  
          MOV    VAR4,#0  
          ACALL  KALI  
          MOV    UANG1,VAR5  
          MOV    UANG2,VAR6  
          MOV    UANG3,VAR7  
          MOV    UANG4,VAR8  
          RET
```

```

;-----[-----]
;      TRANSMISI
;-----[-----]

TRANSMISI MOV R0,#30H
          MOV R2,#8
          MOV A,#128
          JNB TI,$
          CLR TI
TRANS1   MOV A,@R0
          JNB TI,$
          CLR TI
          DJNZ R2,TRANS1
          RET

;-----[-----]
;      MAIN PROGRAM
;-----[-----]

MULAI    MOV SP,#40H
          ACALL DELAY
          MOV DPTR,#PCW
          MOV A,#CW
          MOVX @DPTR,A
          ACALL LCD
          ACALL STRING
          ACALL INIT
CEKDETIK MOV A,WAKTU1
          CJNE A,WAKTU2,CEK      ;CEK PERUBAHAN DETIK
          AJMP DISPLAY
CEK       ACALL HITWATT
          MOV WAKTU2,WAKTU1
          MOV A,WAKTU1
          MOV B,#36
          DIV AB
          MOV WAKTU1,B
          MOV WAKTU2,WAKTU1
          JNB ACC.0,DISPLAY      ;APAKAH WAKTU1 = 36 ?
          ACALL HITKWH
DISPLAY  MOV VAR5,KWH1
          MOV VAR6,KWH2
          MOV VAR7,KWH3
          MOV VAR8,KWH4
          ACALL DISP_KWH
          MOV VAR5,UANG1
          MOV VAR6,UANG2
          MOV VAR7,UANG3
          MOV VAR8,UANG4

```

```
MOV A,#0C0H      ;BARIS 2
ACALL SUB_LCD
ACALL DISP_BIAYA
JB P3.2,CEKDETIK
ACALL TRANSMISI
AJMP CEKDETIK
□
```



National  
Semiconductor  
Corporation

## ADC0801, ADC0802, ADC0803, ADC0804, ADC0805 8-Bit $\mu$ P Compatible A/D Converters

### General Description

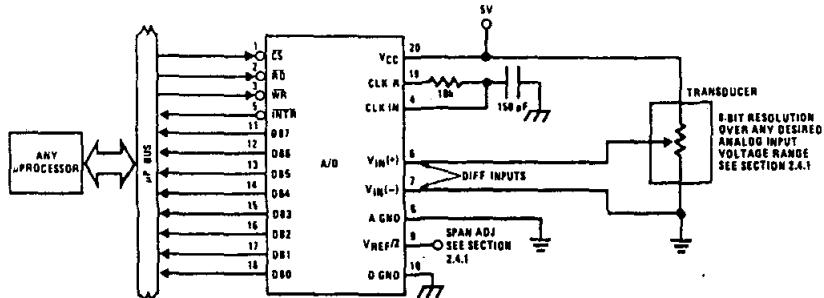
The ADC0801, ADC0802, ADC0803, ADC0804 and ADC0805 are CMOS 8-bit successive approximation A/D converters that use a differential potentiometric ladder—similar to the 256R products. These converters are designed to allow operation with the NSC800 and INS8080A derivative control bus with TRI-STATE® output latches directly driving the data bus. These A/Ds appear like memory locations or I/O ports to the microprocessor and no interfacing logic is needed.

Differential analog voltage inputs allow increasing the common-mode rejection and offsetting the analog zero input voltage value. In addition, the voltage reference input can be adjusted to allow encoding any smaller analog voltage span to the full 8 bits of resolution.

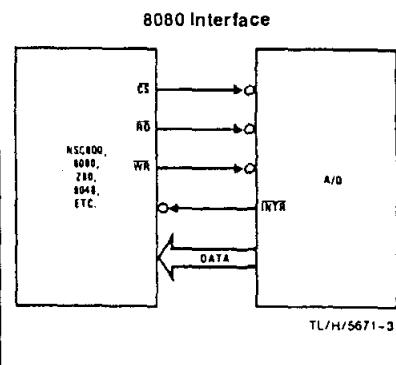
### Features

- Compatible with 8080  $\mu$ P derivatives—no interfacing logic needed • access time • 135 ns
- Easy interface to all microprocessors, or operates "stand alone"

### Typical Applications



TL/H/5671-1



Error Specification (Includes Full-Scale, Zero Error, and Non-Linearity)			
Part Number	Full-Scale Adjusted	$V_{REF}/2 = 2.500 \text{ V}_{DC}$ (No Adjustments)	$V_{REF}/2 = \text{No Connection}$ (No Adjustments)
ADC0801	$\pm \frac{1}{4} \text{ LSB}$		
ADC0802		$\pm \frac{1}{2} \text{ LSB}$	
ADC0803	$\pm \frac{1}{2} \text{ LSB}$		
ADC0804		$\pm 1 \text{ LSB}$	
ADC0805			$\pm 1 \text{ LSB}$

**Electrical Maximum Ratings** (Notes 1 & 2)

Aerospace specified devices are required, see National Semiconductor Sales Office/for availability and specifications.

ge (V<sub>CC</sub>) (Note 3) 6.5V

Control Inputs	-0.3V to +18V
Input and Outputs (Soldering, 10 seconds)	-0.3V to (V <sub>CC</sub> +0.3V)
the Package (plastic)	260°C
the Package (ceramic)	300°C
Mount Package	
Phase (60-seconds) (15 seconds)	215°C 220°C

Storage Temperature Range	-65°C to +150°C
Package Dissipation at T <sub>A</sub> = 25°C	875 mW
ESD Susceptibility (Note 10)	800V
Range of V <sub>CC</sub>	4.5 V <sub>DC</sub> to 6.3 V <sub>DC</sub>

**Operating Ratings** (Notes 1 & 2)

Temperature Range	T <sub>MIN</sub> ≤ T <sub>A</sub> ≤ T <sub>MAX</sub>
ADC0801/02LJ	-55°C ≤ T <sub>A</sub> ≤ +125°C
ADC0801/02/03/04LCJ	-40°C ≤ T <sub>A</sub> ≤ +85°C
ADC0801/02/03/05LCN	-40°C ≤ T <sub>A</sub> ≤ +85°C
ADC0804LCN	0°C ≤ T <sub>A</sub> ≤ +70°C
ADC0802/03/04LCV	0°C ≤ T <sub>A</sub> ≤ +70°C
ADC0802/03/04LCWM	0°C ≤ T <sub>A</sub> ≤ +70°C

**Electrical Characteristics**

Specifications apply for V<sub>CC</sub> = 5 V<sub>DC</sub>, T<sub>MIN</sub> ≤ T<sub>A</sub> ≤ T<sub>MAX</sub> and f<sub>CLK</sub> = 640 kHz unless otherwise specified.

Parameter	Conditions	Min	Typ	Max	Units
Total Adjusted Error (Note 8)	With Full-Scale Adj. (See Section 2.5.2)			± 1/4	LSB
Total Unadjusted Error (Note 8)	V <sub>REF</sub> /2 = 2.500 V <sub>DC</sub>			± 1/2	LSB
Total Adjusted Error (Note 8)	With Full-Scale Adj. (See Section 2.5.2)			± 1/2	LSB
Total Unadjusted Error (Note 8)	V <sub>REF</sub> /2 = 2.500 V <sub>DC</sub>			± 1	LSB
Total Unadjusted Error (Note 8)	V <sub>REF</sub> /2-No Connection			± 1	LSB
I Resistance (Pin 9)	ADC0801/02/03/05 ADC0804 (Note 9)	2.5 0.75	8.0 1.1		kΩ kΩ
Voltage Range	(Note 4) V(+) or V(-)	Gnd-0.05		V <sub>CC</sub> + 0.05	V <sub>DC</sub>
-Mode Error	Over Analog Input Voltage Range		± 1/16	± 1/4	LSB
Sensitivity	V <sub>CC</sub> = 5 V <sub>DC</sub> ± 10% Over Allowed V <sub>IN</sub> (+) and V <sub>IN</sub> (-) Voltage Range (Note 4)		± 1/16	± 1/8	LSB

**Electrical Characteristics**

Specifications apply for V<sub>CC</sub> = 5 V<sub>DC</sub> and T<sub>A</sub> = 25°C unless otherwise specified.

Parameter	Conditions	Min	Typ	Max	Units
Conversion Time	f <sub>CLK</sub> = 640 kHz (Note 6)	103		114	μs
Conversion Time	(Note 5, 6)	66		73	1/f <sub>CLK</sub>
Clock Frequency	V <sub>CC</sub> = 5V, (Note 5)	100	640	1460	kHz
Clock Duty Cycle	(Note 5)	40		60	%
Conversion Rate in Free-Running Mode	INTR tied to WR with CS = 0 V <sub>DC</sub> , f <sub>CLK</sub> = 640 kHz	8770		9708	conv/s
Width of WR Input (Start Pulse Width)	CS = 0 V <sub>DC</sub> (Note 7)	100			ns
Access Time (Delay from Falling Edge of RD to Output Data Valid)	C <sub>L</sub> = 100 pF		135	200	ns
TRI-STATE Control (Delay from Rising Edge of RD to Hi-Z State)	C <sub>L</sub> = 10 pF, R <sub>L</sub> = 10k (See TRI-STATE Test Circuits)		125	200	ns
Delay from Falling Edge of WR or RD to Reset of INTR			300	450	ns
Input Capacitance of Logic Control Inputs			5	7.5	pF
TRI-STATE Output Capacitance (Data Buffers)			5	7.5	pF
PUTS [Note: CLK IN (Pin 4) is the input of a Schmitt trigger circuit and is therefore specified separately]					
Logical "1" Input Voltage (Except Pin 4 CLK IN)	V <sub>CC</sub> = 5.25 V <sub>DC</sub>	2.0		15	V <sub>DC</sub>

**AC Electrical Characteristics (Continued)**

The following specifications apply for  $V_{CC} = 5V_{DC}$  and  $T_{MIN} \leq T_A \leq T_{MAX}$ , unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>CONTROL INPUTS [Note: CLK IN (Pin 4) is the input of a Schmitt trigger circuit and is therefore specified separately]</b>						
$V_{IN}(0)$	Logical "0" Input Voltage (Except Pin 4 CLK IN)	$V_{CC} = 4.75 V_{DC}$			0.8	$V_{DC}$
$I_{IN}(1)$	Logical "1" Input Current (All Inputs)	$V_{IN} = 5 V_{DC}$		0.005	1	$\mu A_{DC}$
$I_{IN}(0)$	Logical "0" Input Current (All Inputs)	$V_{IN} = 0 V_{DC}$	-1	-0.005		$\mu A_{DC}$
<b>CLOCK IN AND CLOCK R</b>						
$V_{T+}$	CLK IN (Pin 4) Positive Going Threshold Voltage		2.7	3.1	3.5	$V_{DC}$
$V_{T-}$	CLK IN (Pin 4) Negative Going Threshold Voltage		1.5	1.8	2.1	$V_{DC}$
$V_H$	CLK IN (Pin 4) Hysteresis $(V_{T+}) - (V_{T-})$		0.6	1.3	2.0	$V_{DC}$
$V_{OUT}(0)$	Logical "0" CLK R Output Voltage	$I_O = 360 \mu A$ $V_{CC} = 4.75 V_{DC}$			0.4	$V_{DC}$
$V_{OUT}(1)$	Logical "1" CLK R Output Voltage	$I_O = -360 \mu A$ $V_{CC} = 4.75 V_{DC}$	2.4			$V_{DC}$
<b>DATA OUTPUTS AND INTR</b>						
$V_{OUT}(0)$	Logical "0" Output Voltage Data Outputs INTR Output	$I_{OUT} = 1.6 mA, V_{CC} = 4.75 V_{DC}$ $I_{OUT} = 1.0 mA, V_{CC} = 4.75 V_{DC}$			0.4	$V_{DC}$
$V_{OUT}(1)$	Logical "1" Output Voltage	$I_O = -360 \mu A, V_{CC} = 4.75 V_{DC}$	2.4			$V_{DC}$
$V_{OUT}(1)$	Logical "1" Output Voltage	$I_O = -10 \mu A, V_{CC} = 4.75 V_{DC}$	4.5			$V_{DC}$
$I_{OUT}$	TRI-STATE Disabled Output Leakage (All Data Buffers)	$V_{OUT} = 0 V_{DC}$ $V_{OUT} = 5 V_{DC}$	-3		3	$\mu A_{DC}$
$I_{SOURCE}$		$V_{OUT}$ Short to Gnd, $T_A = 25^\circ C$	4.5	6		$mA_{DC}$
$I_{SINK}$		$V_{OUT}$ Short to $V_{CC}$ , $T_A = 25^\circ C$	9.0	16		$mA_{DC}$
<b>POWER SUPPLY</b>						
$I_{CC}$	Supply Current (Includes Ladder Current)	$I_{CLK} = 640 kHz,$ $V_{REF}/2 = NC, T_A = 25^\circ C$ and $\overline{CS} = 5V$			1.1	$mA$
	ADC0801/02/03/04LCJ/05 ADC0804LCN/LCV/LCWM				1.9	$mA$

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. DC and AC electrical specifications do not apply when operating the device beyond its specified operating conditions.

Note 2: All voltages are measured with respect to Gnd, unless otherwise specified. The separate A Gnd point should always be wired to the D Gnd.

Note 3: A zener diode exists, internally, from  $V_{CC}$  to Gnd and has a typical breakdown voltage of 7  $V_{DC}$ .

Note 4: For  $V_{IN}(-)$ ,  $V_{IN}(+)$  the digital output code will be 0000 0000. Two on-chip diodes are tied to each analog input (see block diagram) which will forward conduct for analog input voltages one diode drop below ground or one diode drop greater than the  $V_{CC}$  supply. Be careful, during testing at low  $V_{CC}$  levels (4.5V), as high level analog inputs (5V) can cause this input diode to conduct—especially at elevated temperatures, and cause errors for analog inputs near full-scale. The spec allows 50 mV forward bias of either diode. This means that as long as the analog  $V_{IN}$  does not exceed the supply voltage by more than 50 mV, the output code will be correct. To achieve an absolute 0  $V_{DC}$  to 5  $V_{DC}$  input voltage range will therefore require a minimum supply voltage of 4.950  $V_{DC}$  over temperature variations, initial tolerance and loading.

Note 5: Accuracy is guaranteed at  $f_{CLK} = 640 kHz$ . At higher clock frequencies accuracy can degrade. For lower clock frequencies, the duty cycle limits can be extended so long as the minimum clock high time interval or minimum clock low time interval is no less than 275 ns.

Note 6: With an asynchronous start pulse, up to 8 clock periods may be required before the internal clock phases are proper to start the conversion process. The start request is internally latched, see Figure 2 and section 2.0.

Note 7: The  $\overline{CS}$  input is assumed to bracket the WR strobe input and therefore timing is dependent on the WR pulse width. An arbitrarily wide pulse width will hold the converter in a reset mode and the start of conversion is initiated by the low to high transition of the WR pulse (see timing diagrams).

Note 8: None of these A/Ds requires a zero adjust (see section 2.5.1). To obtain zero code at other analog input voltages see section 2.5 and Figure 5.

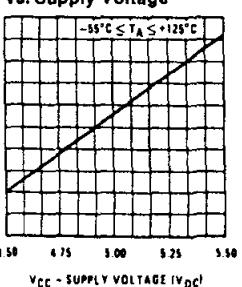
Note 9: The  $V_{REF}/2$  pin is the center point of a two resistor divider connected from  $V_{CC}$  to ground. Each resistor is 2.2k, except for the ADC0804LCJ where each resistor is 16k. Total ladder input resistance is the sum of the two equal resistors.

Note 10: Human body model, 100 pF discharged through a 1.5 k $\Omega$  resistor.

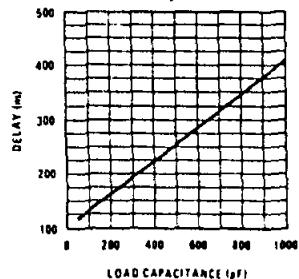
## ADC0801/ADC0802/ADC0803/ADC0804/ADC0805

### Typical Performance Characteristics

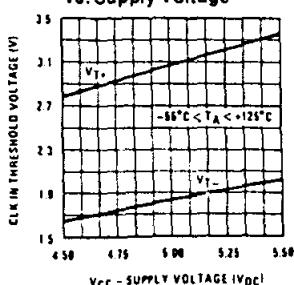
**Logic Input Threshold Voltage vs. Supply Voltage**



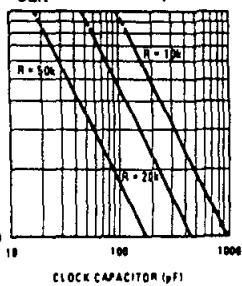
**Delay From Falling Edge of RD to Output Data Valid vs. Load Capacitance**



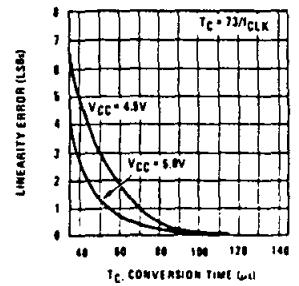
**CLK IN Schmitt Trip Levels vs. Supply Voltage**



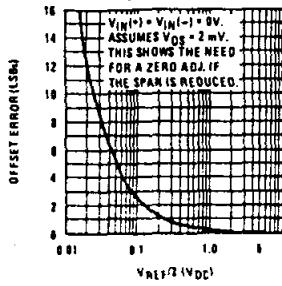
**f<sub>CLK</sub> vs. Clock Capacitor**



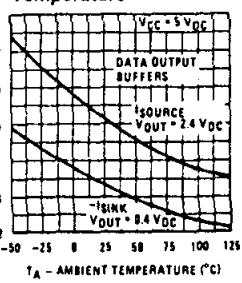
**Full-Scale Error vs. Conversion Time**



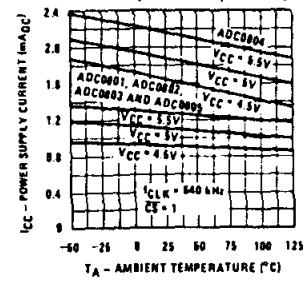
**Effect of Unadjusted Offset Error vs. V<sub>REF/2</sub> Voltage**



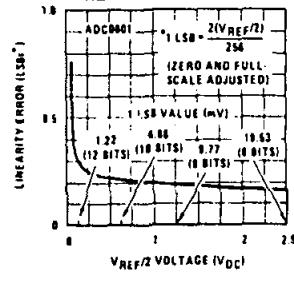
**Output Current vs. Temperature**



**Power Supply Current vs. Temperature (Note 9)**

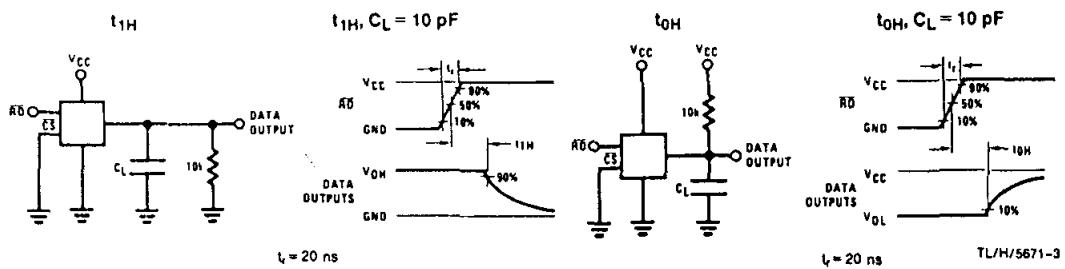


**Linearity Error at Low V<sub>REF/2</sub> Voltages**

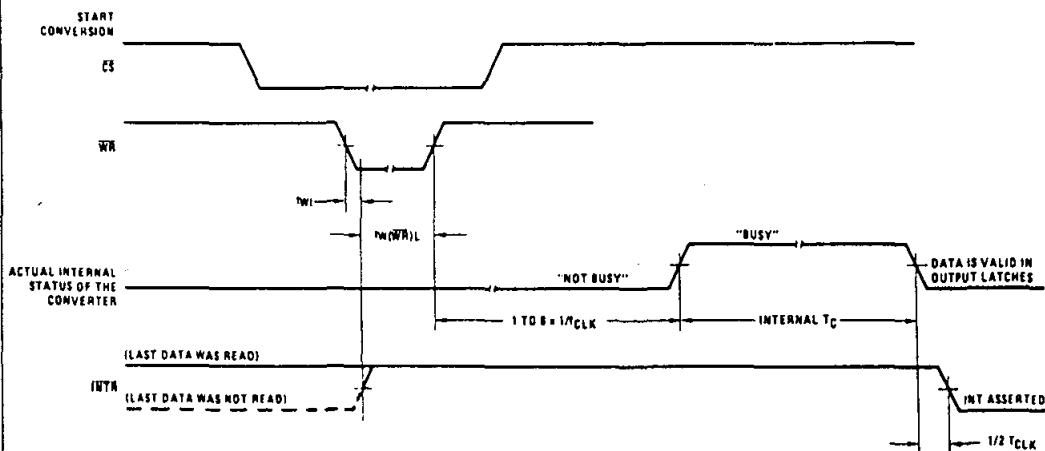


3

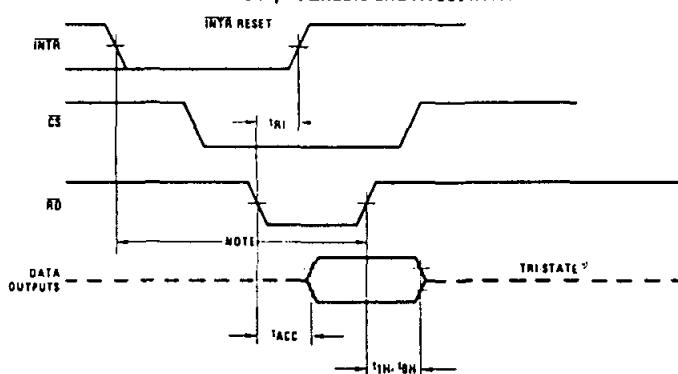
### TRI-STATE Test Circuits and Waveforms



### Timing Diagrams (All timing is measured from the 50% voltage points)



### Output Enable and Reset INTR



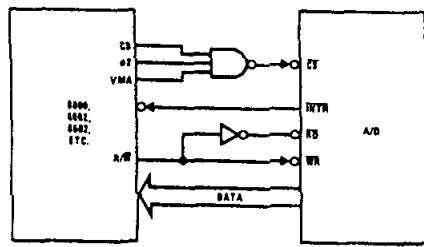
Note: Read strobe must occur 8 clock periods (8/f<sub>CLK</sub>) after assertion of interrupt to guarantee reset of INTR.

TL/H/5671-4

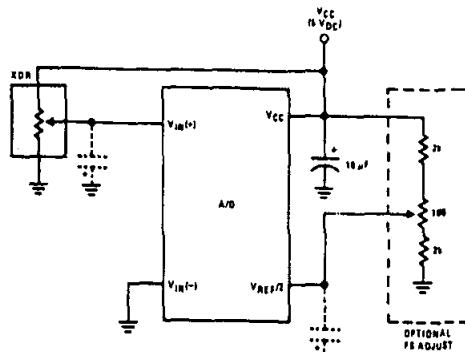
## ADC0801/ADC0802/ADC0803/ADC0804/ADC0805

### Typical Applications (Continued)

#### 6800 Interface

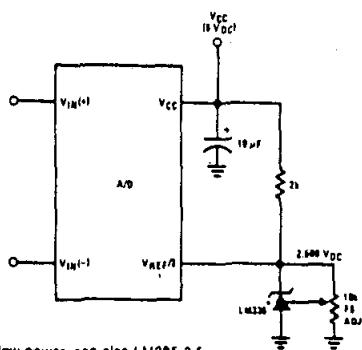


#### Ratiometric with Full-Scale Adjust

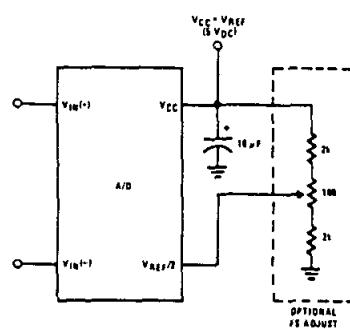


Note: before using caps at  $V_{IN}$  or  $V_{REF}/2$ , see section 2.3.2 Input Bypass Capacitors.

#### Absolute with a 2.500V Reference

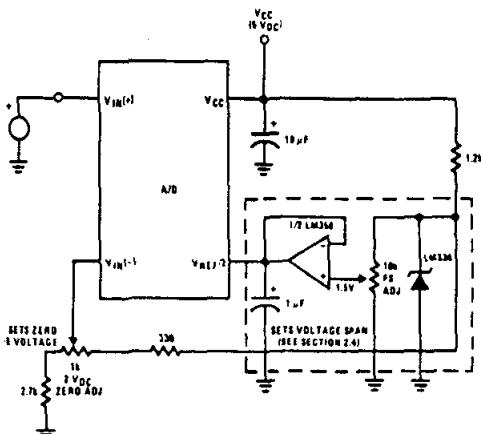


#### Absolute with a 5V Reference

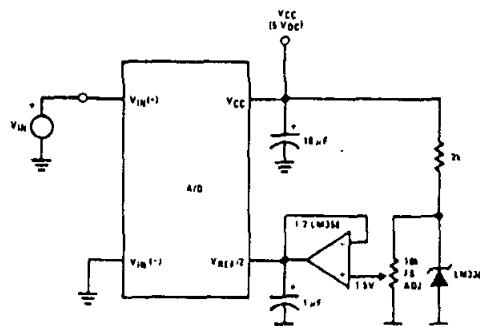


\*For low power, see also LM385-2.5

#### Zero-Shift and Span Adjust: $2V \leq V_{IN} \leq 5V$



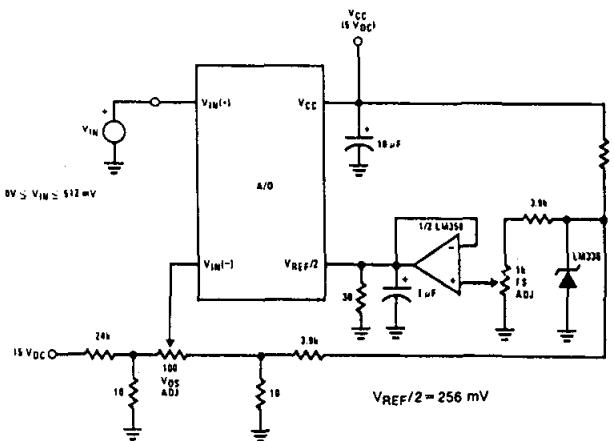
#### Span Adjust: $0V \leq V_{IN} \leq 3V$



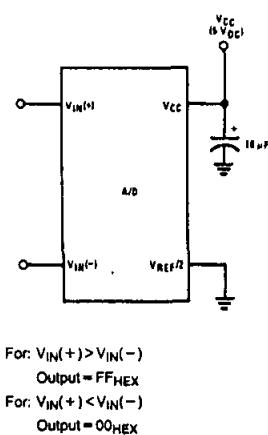
3

## **Typical Applications (Continued)**

### **Directly Converting a Low-Level Signal**

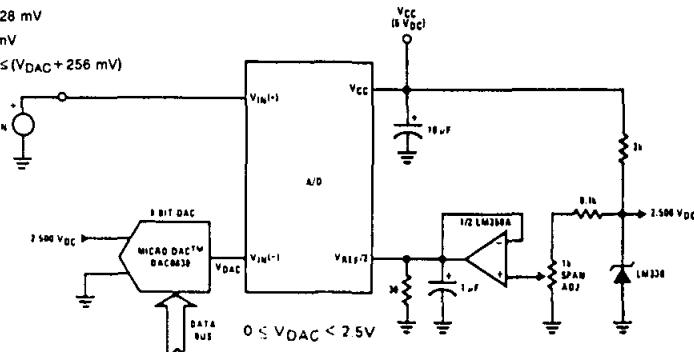


## A μP Interfaced Comparator

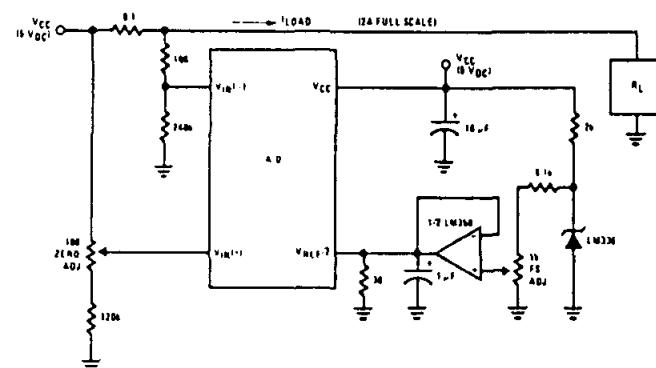


**1 mV Resolution with  $\mu$ P Controlled Range**

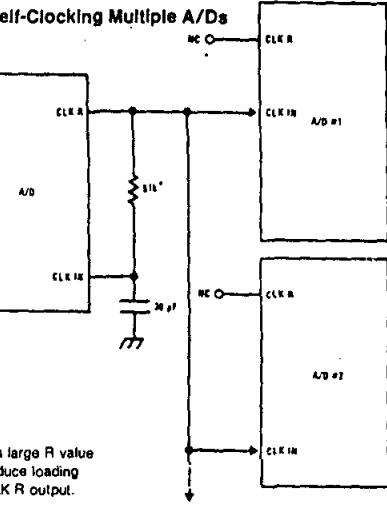
$$\begin{aligned}V_{REF}/2 &= 128 \text{ mV} \\1 \text{ LSB} &= 1 \text{ mV} \\V_{DAC} &\leq V_{IN} \leq (V_{DAC} + 256 \text{ mV})\end{aligned}$$



## Digitizing a Current Flow

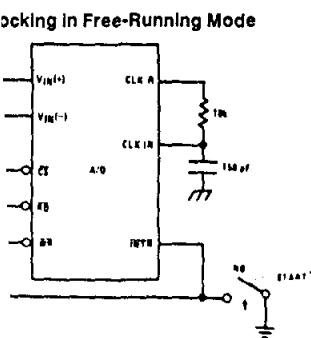


## **Real Applications** (Continued)

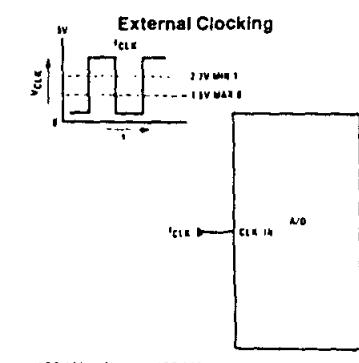


• large R value  
reduce loading  
K/R output

IF MORE THAN \$ ADDITIONAL  
A/D, USE A CMOS BUFFER (NOT T<sub>L</sub>L)

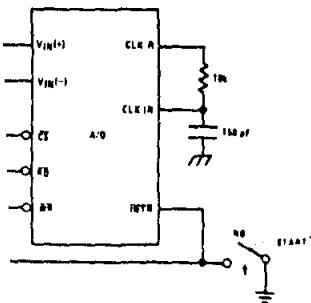


up, a momentary grounding input is needed to guarantee operation.

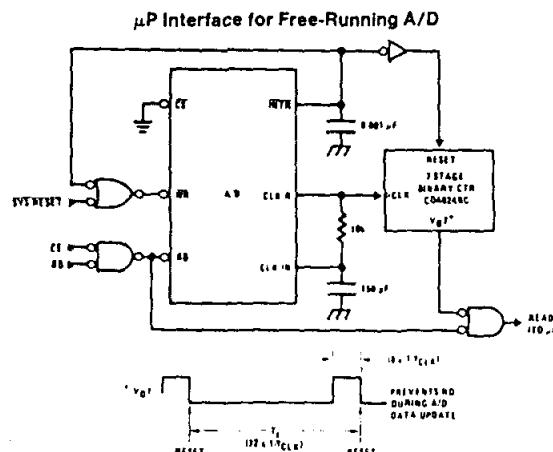


100 kHz < f<sub>cav</sub> < 1460 kHz

## **Locking in Free-Running Mode**

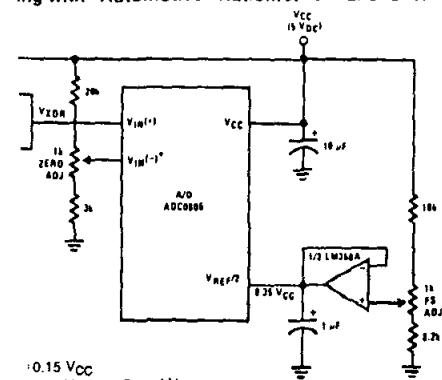


up, a momentary grounding input is needed to guarantee operation.

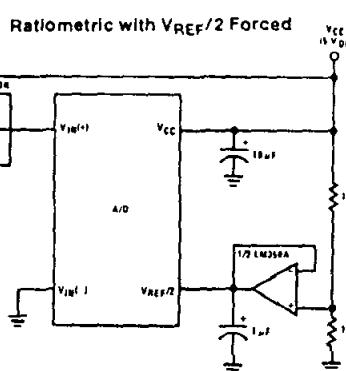


3

#### **ing with "Automotive" Batimetric Transducers**



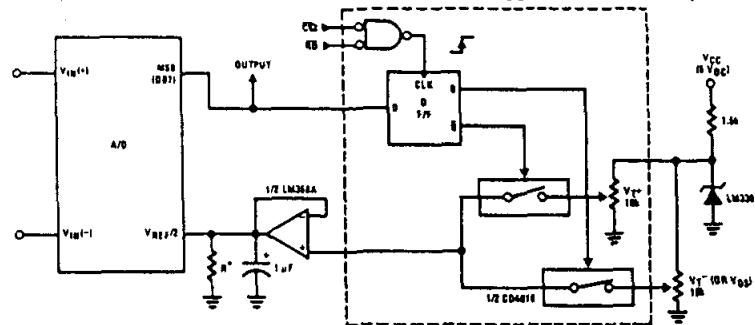
$V_{CC} \leq V_{XDR} \leq 85\% \text{ of } V_{CC}$



TL/H/5671-7

### Typical Applications (Continued)

**$\mu$ P Compatible Differential-Input Comparator with Pre-Set  $V_{OS}$  (with or without Hysteresis)**

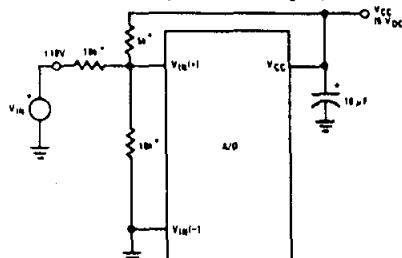


\*See Figure 5 to select R value

DB7 = "1" for  $V_{IN(+)} > V_{IN(-)} + (V_{REF}/2)$

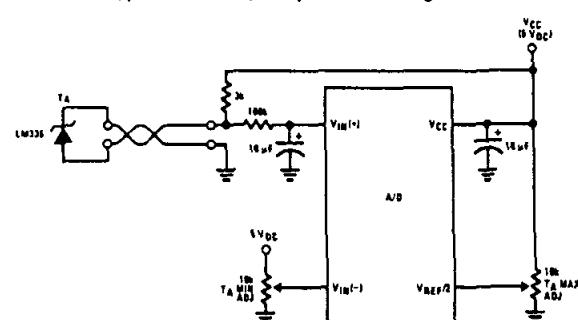
Omit circuitry within the dotted area if hysteresis is not needed

**Handling  $\pm 10$  V Analog Inputs**

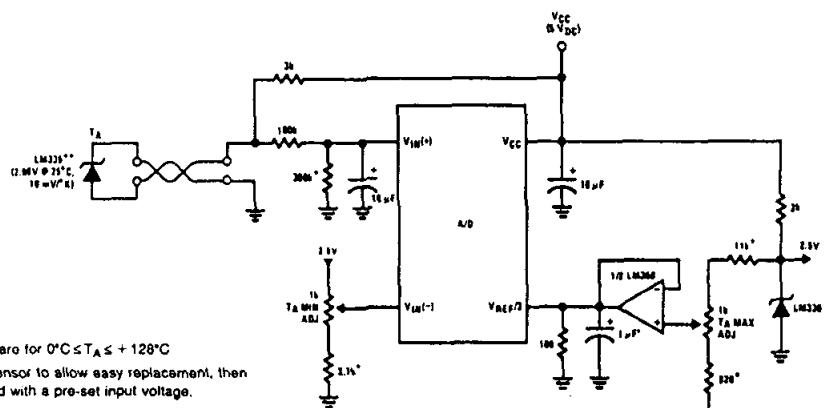


\*Beckman Instruments # 694-3-R10K resistor array

**Low-Cost,  $\mu$ P Interfaced, Temperature-to-Digital Converter**



**$\mu$ P Interfaced Temperature-to-Digital Converter**



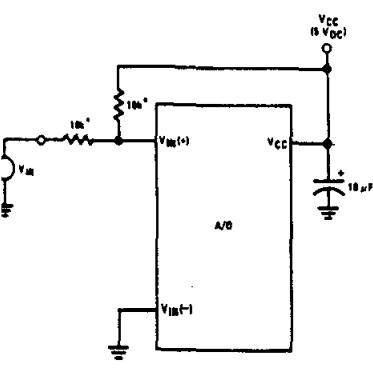
\*Circuit values shown are for  $0^\circ\text{C} \leq T_A \leq +128^\circ\text{C}$

\*\*Can calibrate each sensor to allow easy replacement, then A/D can be calibrated with a pre-set input voltage.

## ADC0801/ADC0802/ADC0803/ADC0804/ADC0805

### cal Applications (Continued)

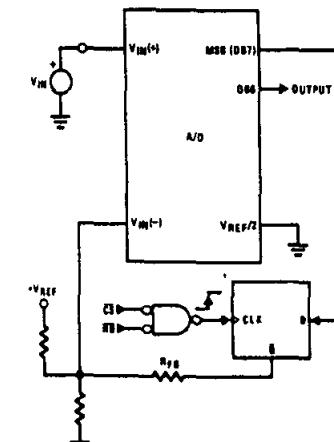
#### Handling $\pm 5V$ Analog Inputs



TL/H/5671-33

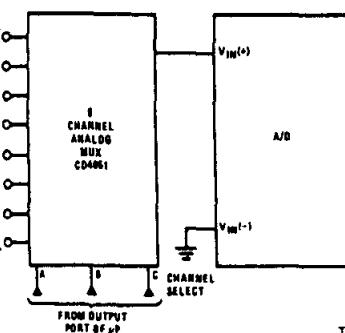
\*Beckman Instruments #694-3-R10K resistor array

#### $\mu P$ Interfaced Comparator with Hysteresis



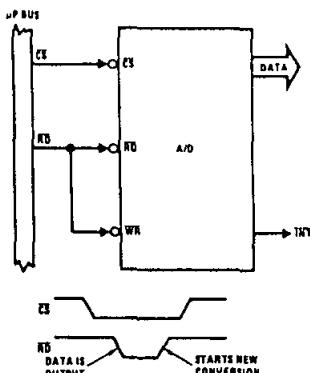
TL/H/5671-35

#### Analog Self-Test for a System



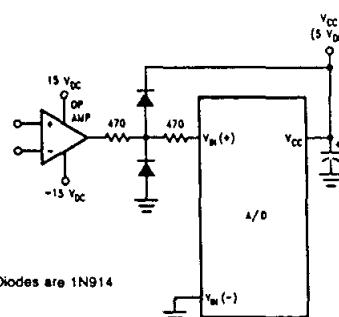
TL/H/5671-36

#### Read-Only Interface



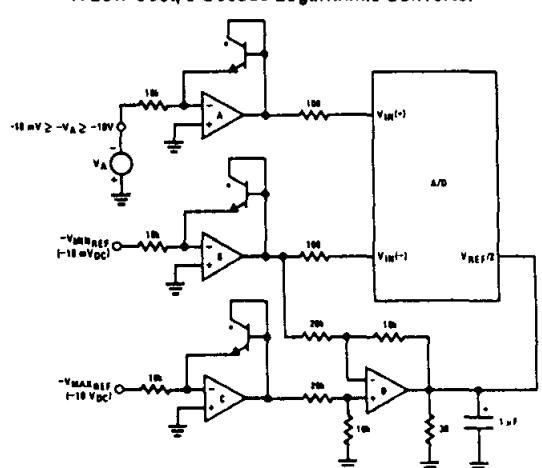
TL/H/5671-34

#### Protecting the Input



TL/H/5671-9

#### A Low-Cost, 3-Decade Logarithmic Converter



TL/H/5671-37

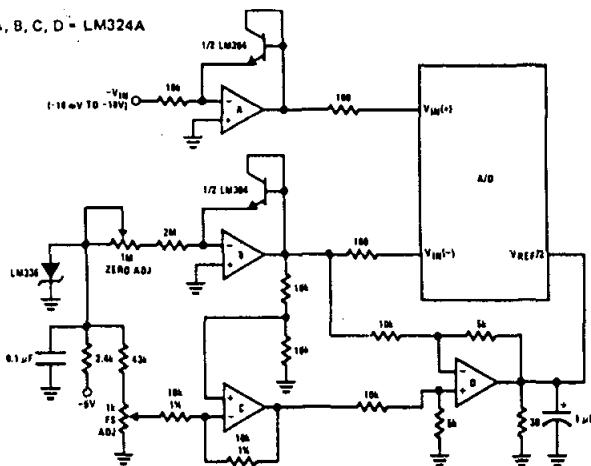
\*LM389 transistors  
A, B, C, D = LM324A quad op amp

3

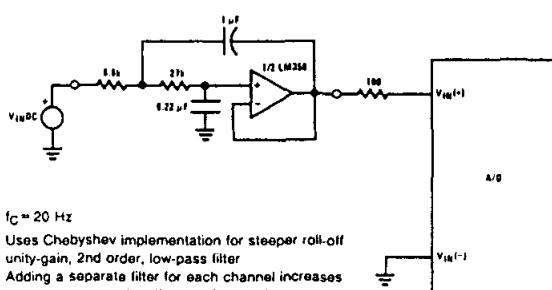
## Typical Applications (Continued)

### **3-Decade Logarithmic A/D Converter**

A, B, C, D = LM324A



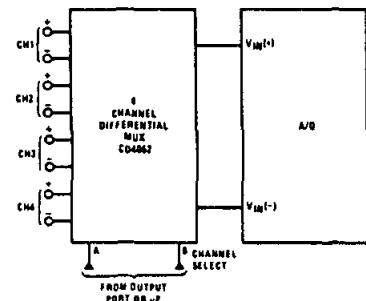
### Noise Filtering the Analog Input



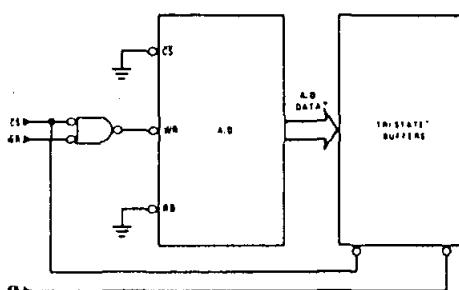
$$f_C \approx 20 \text{ Hz}$$

Uses Chebyshev implementation for steeper roll-off unity-gain, 2nd order, low-pass filter  
Adding a separate filter for each channel increases system response time if an analog multiplexer is used

## Multiplexing Differential Inputs

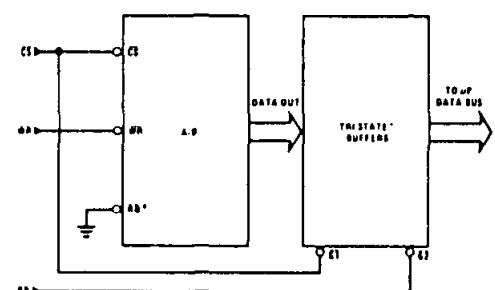


### **Output Buffers with A/D Data Enabled**

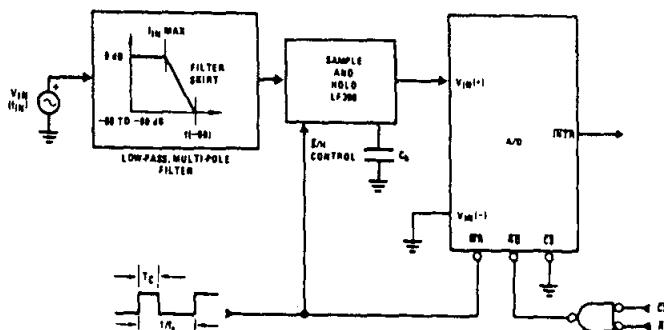


\*A/D output data is updated 1 CLK period prior to assertion of INT&

#### **Increasing Bus Drive and/or Reducing Time on Bus**

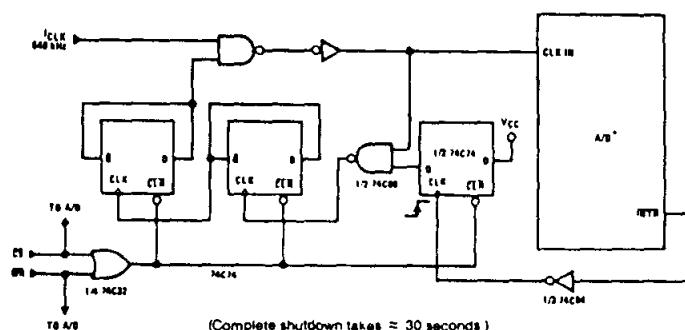
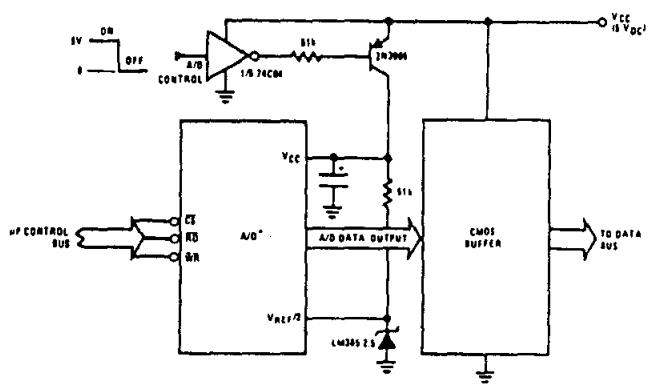


\*Allows output data to set-up at falling edge of CS

**Typical Applications (Continued)****Sampling an AC Input Signal**

Note 1: Oversample whenever possible [keep  $f_s > 2f(-60)$ ] to eliminate input frequency folding (aliasing) and to allow for the skirt response of the filter.

Note 2: Consider the amplitude errors which are introduced within the passband of the filter.

**70% Power Savings by Clock Gating****Power Savings by A/D and V<sub>REF</sub> Shutdown**

3

TL/H/5671-11

\*Use ADC0801, 02, 03 or 05 for lowest power consumption.

Note: Logic Inputs can be driven to V<sub>CC</sub> with A/D supply at zero volts.

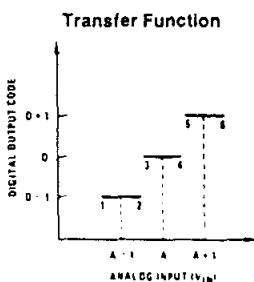
Buffer prevents data bus from overdriving output of A/D when in shutdown mode.

## Functional Description

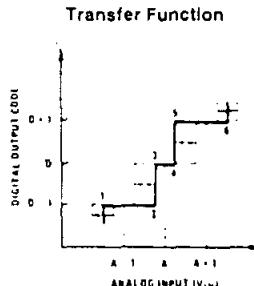
### 1.0 UNDERSTANDING A/D ERROR SPECS

A perfect A/D transfer characteristic (staircase waveform) is shown in *Figure 1a*. The horizontal scale is analog input voltage and the particular points labeled are in steps of 1 LSB (19.53 mV with 2.5V tied to the  $V_{REF}/2$  pin). The digital output codes that correspond to these inputs are shown as D-1, D, and D+1. For the perfect A/D, not only will center-value ( $A-1, A, A+1, \dots$ ) analog inputs produce the correct output digital codes, but also each riser (the transitions between adjacent output codes) will be located  $\pm 1/2$  LSB away from each center-value. As shown, the risers are ideal and have no width. Correct digital output codes will be provided for a range of analog input voltages that extend  $\pm 1/2$  LSB from the ideal center-values. Each tread (the range of analog input voltage that provides the same digital output code) is therefore 1 LSB wide.

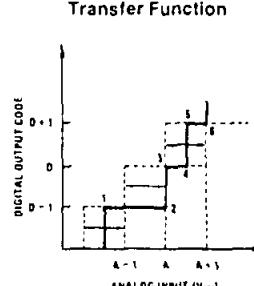
*Figure 1b* shows a worst case error plot for the ADC0801. All center-valued inputs are guaranteed to produce the correct output codes and the adjacent risers are guaranteed to be no closer to the center-value points than  $\pm 1/4$  LSB. In



a) Accuracy =  $\pm 0$  LSB: A Perfect A/D



b) Accuracy =  $\pm 1/4$  LSB



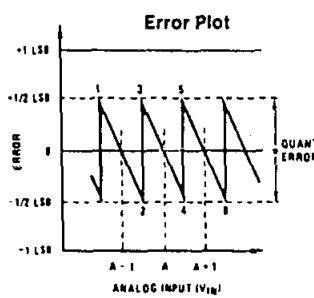
c) Accuracy =  $\pm 1/2$  LSB

FIGURE 1. Clarifying the Error Specs of an A/D Converter

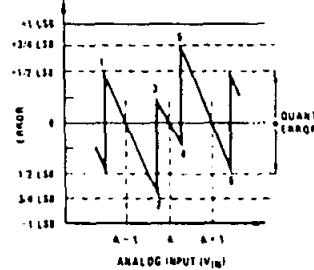
other words, if we apply an analog input equal to the center-value  $\pm 1/4$  LSB, we guarantee that the A/D will produce the correct digital code. The maximum range of the position of the code transition is indicated by the horizontal arrow and it is guaranteed to be no more than  $1/2$  LSB.

The error curve of *Figure 1c* shows a worst case error plot for the ADC0801. Here we guarantee that if we apply an analog input equal to the LSB analog voltage center-value the A/D will produce the correct digital code.

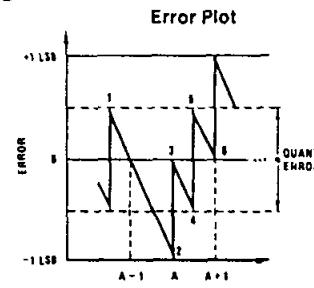
Next to each transfer function is shown the corresponding error plot. Many people may be more familiar with error plots than transfer functions. The analog input voltage to the A/D is provided by either a linear ramp or by the discrete output steps of a high resolution DAC. Notice that the error is continuously displayed and includes the quantization uncertainty of the A/D. For example the error at point 1 of *Figure 1a* is  $+1/2$  LSB because the digital code appeared  $1/2$  LSB in advance of the center-value of the tread. The error plots always have a constant negative slope and the abrupt upside steps are always 1 LSB in magnitude.



Error Plot



Error Plot



Error Plot

## Functional Description (Continued)

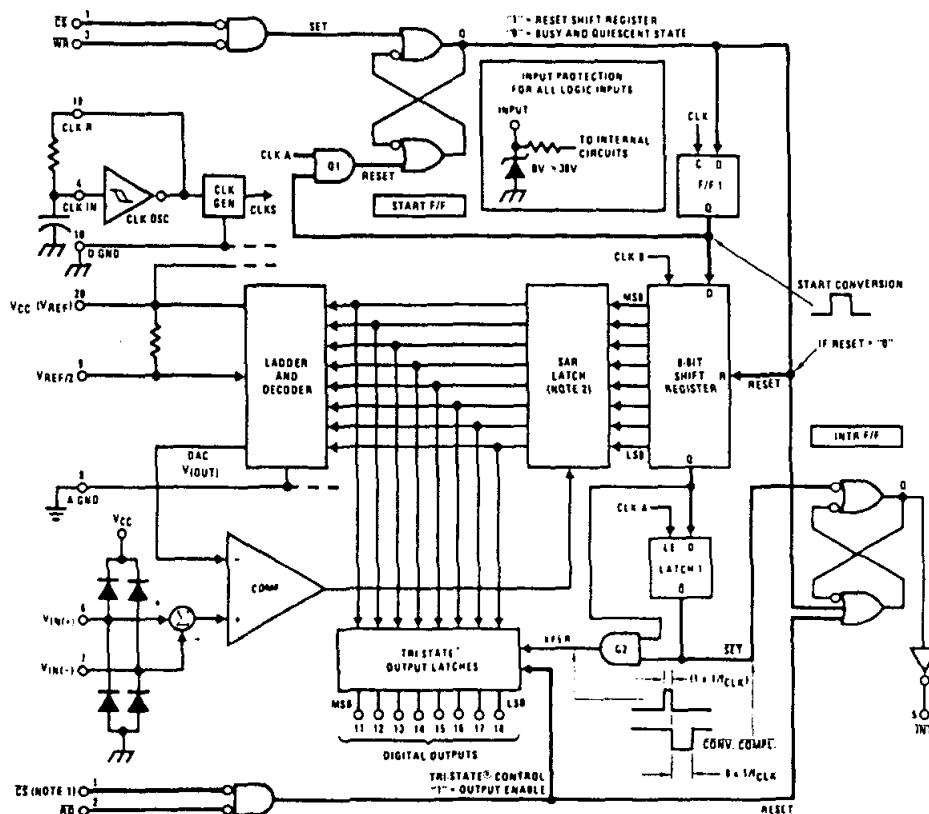
### 2.0 FUNCTIONAL DESCRIPTION

The ADC0801 series contains a circuit equivalent of the 256R network. Analog switches are sequenced by successive approximation logic to match the analog difference input voltage ( $V_{IN(+)} - V_{IN(-)}$ ) to a corresponding tap on the R network. The most significant bit is tested first and after 8 comparisons (64 clock cycles) a digital 8-bit binary code (1111 1111 = full-scale) is transferred to an output latch and then an interrupt is asserted ( $\text{INTR}$  makes a high-to-low transition). A conversion in process can be interrupted by issuing a second start command. The device may be operated in the free-running mode by connecting  $\text{INTR}$  to the  $\text{WR}$  input with  $\text{CS} = 0$ . To ensure start-up under all possible conditions, an external  $\text{WR}$  pulse is required during the first power-up cycle.

On the high-to-low transition of the  $\text{WR}$  input the internal SAR latches and the shift register stages are reset. As long as the  $\text{CS}$  input and  $\text{WR}$  input remain low, the A/D will remain in a reset state. Conversion will start from 1 to 8 clock periods after at least one of these inputs makes a low-to-high transition.

A functional diagram of the A/D converter is shown in Figure 2. All of the package pinouts are shown and the major logic control paths are drawn in heavier weight lines.

The converter is started by having  $\text{CS}$  and  $\text{WR}$  simultaneously low. This sets the start flip-flop ( $\text{F/F}$ ) and the resulting "1" level resets the 8-bit shift register, resets the Interrupt ( $\text{INTR}$ )  $\text{F/F}$  and inputs a "1" to the D flop,  $\text{F/F1}$ , which is at the input end of the 8-bit shift register. Internal clock signals then transfer this "1" to the Q output of  $\text{F/F1}$ . The AND gate,  $\text{G}_1$ , combines this "1" output with a clock signal to provide a reset signal to the start  $\text{F/F}$ . If the set signal is no longer present (either  $\text{WR}$  or  $\text{CS}$  is a "1") the start  $\text{F/F}$  is reset, and the 8-bit shift register then can have the "1" clocked in, which starts the conversion process. If the set signal were to still be present, this reset pulse would have no effect (both outputs of the start  $\text{F/F}$  would momentarily be at a "1" level) and the 8-bit shift register would continue to be held in the reset mode. This logic therefore allows for wide  $\text{CS}$  and  $\text{WR}$  signals and the converter will start after at least one of these signals returns high and the internal clocks again provide a reset signal for the start  $\text{F/F}$ .



Note 1:  $\text{CS}$  shown twice for clarity.

Note 2: SAR = Successive Approximation Register.

FIGURE 2. Block Diagram

## Functional Description (Continued)

After the "1" is clocked through the 8-bit shift register (which completes the SAR search) it appears as the input to the D-type latch, LATCH 1. As soon as this "1" is output from the shift register, the AND gate, G2, causes the new digital word to transfer to the TRI-STATE output latches. When LATCH 1 is subsequently enabled, the Q output makes a high-to-low transition which causes the INTR F/F to set. An inverting buffer then supplies the INTR input signal.

Note that this SET control of the INTR F/F remains low for 8 of the external clock periods (as the internal clocks run at  $\frac{1}{2}$  of the frequency of the external clock). If the data output is continuously enabled ( $\overline{CS}$  and  $\overline{RD}$  both held low), the INTR output will still signal the end of conversion (by a high-to-low transition), because the SET input can control the Q output of the INTR F/F even though the RESET input is constantly at a "1" level in this operating mode. This INTR output will therefore stay low for the duration of the SET signal, which is 8 periods of the external clock frequency (assuming the A/D is not started during this interval).

When operating in the free-running or continuous conversion mode (INTR pin tied to WR and CS wired low—see also section 2.8), the START F/F is SET by the high-to-low transition of the INTR signal. This resets the SHIFT REGISTER which causes the input to the D-type latch, LATCH 1, to go low. As the latch enable input is still present, the Q output will go high, which then allows the INTR F/F to be RESET. This reduces the width of the resulting INTR output pulse to only a few propagation delays (approximately 300 ns).

When data is to be read, the combination of both CS and RD being low will cause the INTR F/F to be reset and the TRI-STATE output latches will be enabled to provide the 8-bit digital outputs.

### 2.1 Digital Control Inputs

The digital control inputs ( $\overline{CS}$ ,  $\overline{RD}$ , and  $\overline{WR}$ ) meet standard T2L logic voltage levels. These signals have been renamed when compared to the standard A/D Start and Output Enable labels. In addition, these inputs are active low to allow an easy interface to microprocessor control busses. For non-microprocessor based applications, the CS input (pin 1) can be grounded and the standard A/D Start function is obtained by an active low pulse applied at the WR input (pin 3) and the Output Enable function is caused by an active low pulse at the RD input (pin 2).

### 2.2 Analog Differential Voltage Inputs and Common-Mode Rejection

This A/D has additional applications flexibility due to the analog differential voltage input. The  $V_{IN(+)}$  input (pin 7) can be used to automatically subtract a fixed voltage value from the input reading (tare correction). This is also useful in 4 mA-20 mA current loop conversion. In addition, common-mode noise can be reduced by use of the differential input. The time interval between sampling  $V_{IN(+)}$  and  $V_{IN(-)}$  is 4½ clock periods. The maximum error voltage due to this

slight time difference between the input voltage samples is given by:

$$\Delta V_e(\text{MAX}) = (V_p) \left( \frac{2\pi f_{cm}}{f_{CLK}} \right) \left( \frac{4.5}{f_{cm} + f_{CLK}} \right),$$

where:

- $\Delta V_e$  is the error voltage due to sampling delay
- $V_p$  is the peak value of the common-mode voltage
- $f_{cm}$  is the common-mode frequency

As an example, to keep this error to  $\frac{1}{4}$  LSB ( $\sim 5$  mV) when operating with a 60 Hz common-mode frequency,  $f_{cm}$ , and using a 640 kHz A/D clock,  $f_{CLK}$ , would allow a peak value of the common-mode voltage,  $V_p$ , which is given by:

$$V_p = \frac{[\Delta V_e(\text{MAX})] (f_{CLK})}{(2\pi f_{cm}) (4.5)}$$

or

$$V_p = \frac{(5 \times 10^{-3}) (640 \times 10^3)}{(6.28) (60) (4.5)}$$

which gives

$$V_p \approx 1.9V.$$

The allowed range of analog input voltages usually places more severe restrictions on input common-mode noise levels.

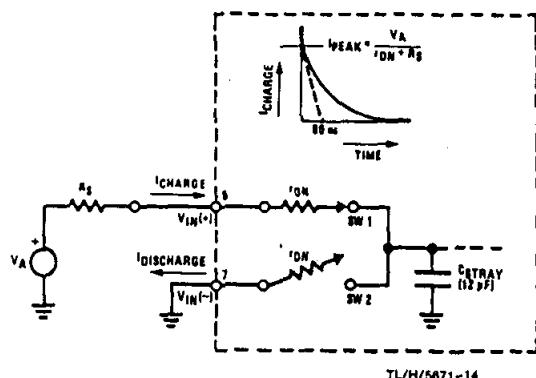
An analog input voltage with a reduced span and a relatively large zero offset can be handled easily by making use of the differential input (see section 2.4 Reference Voltage).

### 2.3 Analog Inputs

#### 2.3.1 Input Current

##### Normal Mode

Due to the internal switching action, displacement currents will flow at the analog inputs. This is due to on-chip stray capacitance to ground as shown in Figure 3.



TLH/5071-14  
 $t_{ON}$  of SW 1 and SW 2  $\approx 5$  k $\Omega$   
 $t_{ON} C_{STRAY} = 5$  k $\Omega \times 12$  pF = 60 ns

FIGURE 3. Analog Input Impedance

### **Functional Description (Continued)**

age on this capacitance is switched and will result in entering the  $V_{IN}(+)$  input pin and leaving the output which will depend on the analog differential stage levels. These current transients occur at the edge of the internal clocks. They rapidly decay and cause errors as the on-chip comparator is strobed at the end of the clock period.

Voltage source applied to the  $V_{IN}(+)$  or  $V_{IN}(-)$  pin in the allowed operating range of  $V_{CC} + 50$  mV, large currents can flow through a parasitic diode to the  $V_{CC}$  pin. These currents can exceed the 1 mA max allowed. An external diode (1N914) should be added to bypass current to the  $V_{CC}$  pin (with the current bypassed with the voltage at the  $V_{IN}(+)$  pin can exceed the rating by the forward voltage of this diode).

#### **Without Bypass Capacitors**

capacitors at the inputs will average these charges into a DC current to flow through the output resistor and the analog signal sources. This charge pumping is worse for continuous conversions with the  $V_{IN}(+)$  stage at full-scale. For continuous conversions with a 1 Hz clock frequency with the  $V_{IN}(+)$  input at 5 V, this current is at a maximum of approximately 5  $\mu$ A. Therefore, *bypass capacitors should not be used at the analog input or the  $V_{REF}/2$  pin for high resistance sources ( $> 1 \text{ M}\Omega$ )*. Input bypass capacitors are necessary for noise filtering. High source resistance is desirable to minimize capacitor size, the detrimental effects of the voltage drop across this input resistance, which is due to the average input current, can be eliminated with a full-scale current while the given source resistor and input bypass capacitors are both in place. This is possible because the average value of the input current is a precise linear function of the differential input voltage.

### **about Source Resistance**

values of source resistance where an input bypass or is not used, will not cause errors as the input current will settle out prior to the comparison time. If a low pass filter is required in the system, use a low valued series resistor ( $1\text{ k}\Omega$ ) for a passive RC section or add an op amp RC low pass filter. For low source resistance applications ( $1\text{ k}\Omega$ ), a  $0.1\text{ }\mu\text{F}$  bypass capacitor at the inputs will reduce noise pickup due to series lead inductance of a long  $100\Omega$  series resistor can be used to isolate this case - both the R and C are placed outside the feedback loop from the output of an op amp, if used.

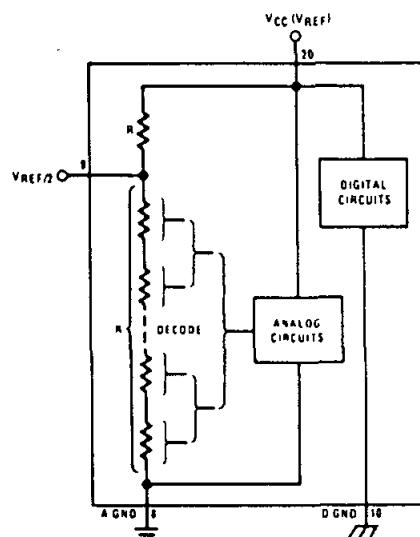
use  
ds to the analog inputs (pin 6 and 7) should be kept as possible to minimize input noise coupling. Both undesired digital clock coupling to these inputs cause system errors. The source resistance for these should, in general, be kept below 5 k $\Omega$ . Larger values cause resistance can cause undesired system noise. Input bypass capacitors, placed from the analog input ground, will eliminate system noise pickup but can cause analog scale errors as these capacitors will average transient input switching currents of the A/D (see section 1.). This scale error depends on both a large source

resistance and the use of an input bypass capacitor. This error can be eliminated by doing a full-scale adjustment of the A/D (adjust  $VREF/2$  for a proper full-scale reading—see section 2.5.2 on Full-Scale Adjustment) with the source resistance and input bypass capacitor in place.

## 2.4 Reference Voltage

#### 2.4.1 Span Adjust

For maximum applications flexibility, these A/Ds have been designed to accommodate a 5 V<sub>DC</sub>, 2.5 V<sub>DC</sub> or an adjusted voltage reference. This has been achieved in the design of the IC as shown in *Figure 4*.

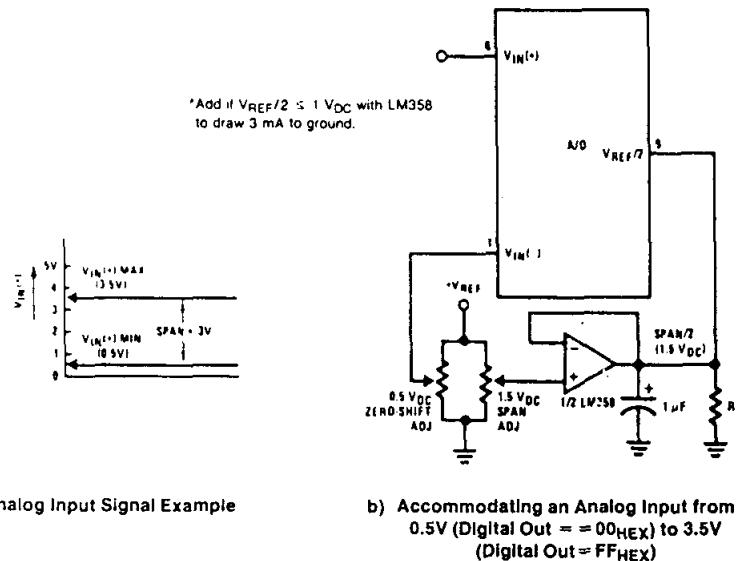


**FIGURE 4.** The Yossefus Design on the IC.

Notice that the reference voltage for the IC is either  $\frac{1}{2}$  of the voltage applied to the  $V_{CC}$  supply pin, or is equal to the voltage that is externally forced at the  $V_{REF/2}$  pin. This allows for a ratiometric voltage reference using the  $V_{CC}$  supply, a 5 V<sub>DC</sub> reference voltage can be used for the  $V_{CC}$  supply or a voltage less than 2.5 V<sub>DC</sub> can be applied to the  $V_{REF/2}$  input for increased application flexibility. The internal gain to the  $V_{REF/2}$  input is 2, making the full-scale differential input voltage twice the voltage at pin 9.

An example of the use of an adjusted reference voltage is to accommodate a reduced span—or dynamic voltage range—of the analog input voltage. If the analog input voltage were to range from 0.5 V<sub>DC</sub> to 3.5 V<sub>DC</sub>, instead of 0V to 5 V<sub>DC</sub>, the span would be 3V as shown in Figure 5. With 0.5 V<sub>DC</sub> applied to the V<sub>IN</sub>(-) pin to absorb the offset, the reference voltage can be made equal to 1/2 of the 3V span or 1.5 V<sub>DC</sub>. The A/D now will encode the V<sub>IN</sub>(+) signal from 0.5V to 3.5V with the 0.5V input corresponding to zero and the 3.5 V<sub>DC</sub> input corresponding to full-scale. The full 8 bits of resolution are therefore applied over this reduced analog input voltage range.

## Functional Description (Continued)



TL/H/5671-16

FIGURE 5. Adapting the A/D Analog Input Voltages to Match an Arbitrary Input Signal Range

### 2.4.2 Reference Accuracy Requirements

The converter can be operated in a ratiometric mode or an absolute mode. In ratiometric converter applications, the magnitude of the reference voltage is a factor in both the output of the source transducer and the output of the A/D converter and therefore cancels out in the final digital output code. The ADC0805 is specified particularly for use in ratiometric applications with no adjustments required. In absolute conversion applications, both the initial value and the temperature stability of the reference voltage are important factors in the accuracy of the A/D converter. For  $V_{REF}/2$  voltages of 2.4 V<sub>DC</sub> nominal value, initial errors of  $\pm 10$  mV<sub>DC</sub> will cause conversion errors of  $\pm 1$  LSB due to the gain of 2 of the  $V_{REF}/2$  input. In reduced span applications, the initial value and the stability of the  $V_{REF}/2$  input voltage become even more important. For example, if the span is reduced to 2.5V, the analog input LSB voltage value is correspondingly reduced from 20 mV (5V span) to 10 mV and 1 LSB at the  $V_{REF}/2$  input becomes 5 mV. As can be seen, this reduces the allowed initial tolerance of the reference voltage and requires correspondingly less absolute change with temperature variations. Note that spans smaller than 2.5V place even tighter requirements on the initial accuracy and stability of the reference source.

In general, the magnitude of the reference voltage will require an initial adjustment. Errors due to an improper value of reference voltage appear as full-scale errors in the A/D transfer function. IC voltage regulators may be used for references if the ambient temperature changes are not excessive. The LM336B 2.5V IC reference diode (from National Semiconductor) has a temperature stability of 1.8 mV typ (6 mV max) over  $0^\circ C \leq T_A \leq +70^\circ C$ . Other temperature range parts are also available.

### 2.5 Errors and Reference Voltage Adjustments

#### 2.5.1 Zero Error

The zero of the A/D does not require adjustment. If the minimum analog input voltage value,  $V_{IN(MIN)}$ , is not ground, a zero offset can be done. The converter can be made to output 0000 0000 digital code for this minimum input voltage by biasing the A/D  $V_{IN(-)}$  input at this  $V_{IN(MIN)}$  value (see Applications section). This utilizes the differential mode operation of the A/D.

The zero error of the A/D converter relates to the location of the first riser of the transfer function and can be measured by grounding the  $V_{IN(-)}$  input and applying a small magnitude positive voltage to the  $V_{IN(+)}$  input. Zero error is the difference between the actual DC input voltage that is necessary to just cause an output digital code transition from 0000 0000 to 0000 0001 and the ideal  $1/2$  LSB value ( $1/2$  LSB = 9.8 mV for  $V_{REF}/2 = 2.500$  V<sub>DC</sub>).

#### 2.5.2 Full-Scale

The full-scale adjustment can be made by applying a differential input voltage that is  $1/2$  LSB less than the desired analog full-scale voltage range and then adjusting the magnitude of the  $V_{REF}/2$  input (pin 9 or the  $V_{CC}$  supply if pin 9 is not used) for a digital output code that is just changing from 1111 1110 to 1111 1111.

## Functional Description (Continued)

### 5.3 Adjusting for an Arbitrary Analog Input Voltage Range

The analog zero voltage of the A/D is shifted away from ground (for example, to accommodate an analog input signal that does not go to ground) this new zero reference should be properly adjusted first. A  $V_{IN(+)}$  voltage that equals this desired zero reference plus  $\frac{1}{2}$  LSB (where the LSB is calculated for the desired analog span, 1 LSB = analog span/256) is applied to pin 6 and the zero reference voltage at pin 7 should then be adjusted to just obtain the 0HEX to 01HEX code transition.

The full-scale adjustment should then be made (with the proper  $V_{IN(-)}$  voltage applied) by forcing a voltage to the  $V_{IN(+)}$  input which is given by:

$$V_{IN(+)} \text{ fs adj} = V_{MAX} - 1.5 \left[ \frac{(V_{MAX} - V_{MIN})}{256} \right],$$

here:

$V_{MAX}$  = The high end of the analog input range

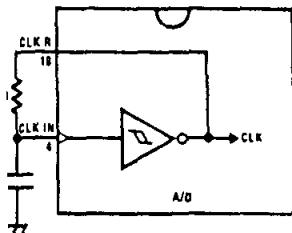
and

$V_{MIN}$  = the low end (the offset zero) of the analog range. Both are ground referenced.)

The  $V_{REF}/2$  (or  $V_{CC}$ ) voltage is then adjusted to provide a code change from FE<sub>HEX</sub> to FF<sub>HEX</sub>. This completes the adjustment procedure.

### 6 Clocking Option

The clock for the A/D can be derived from the CPU clock or an external RC can be added to provide self-clocking. The CLK IN (pin 4) makes use of a Schmitt trigger as shown in figure 6.



$$t_{CLK} \approx \frac{1}{1.1 RC}$$

$R \geq 10 \text{ k}\Omega$

TL/H5671-17

FIGURE 6. Self-Clocking the A/D

Savvy capacitive or DC loading of the clock R pin should be avoided as this will disturb normal converter operation. Loads less than 50 pF, such as driving up to 7 A/D converters clock inputs from a single clock R pin of 1 converter, are allowed. For larger clock line loading, a CMOS or low power TTL buffer or PNP input logic should be used to minimize the loading on the clock R pin (do not use a standard TTL inverter).

### 7 Restart During a Conversion

If the A/D is restarted ( $CS$  and  $WR$  go low and return high) during a conversion, the converter is reset and a new conversion is started. The output data latch is not updated if the

conversion in process is not allowed to be completed, therefore the data of the previous conversion remains in this latch. The  $INTR$  output simply remains at the "1" level.

### 2.8 Continuous Conversions

For operation in the free-running mode an initializing pulse should be used, following power-up, to ensure circuit operation. In this application, the  $CS$  input is grounded and the  $WR$  input is tied to the  $INTR$  output. This  $WR$  and  $INTR$  node should be momentarily forced to logic low following a power-up cycle to guarantee operation.

### 2.9 Driving the Data Bus

This MOS A/D, like MOS microprocessors and memories, will require a bus driver when the total capacitance of the data bus gets large. Other circuitry, which is tied to the data bus, will add to the total capacitive loading, even in TRI-STATE (high impedance mode). Backplane bussing also greatly adds to the stray capacitance of the data bus.

There are some alternatives available to the designer to handle this problem. Basically, the capacitive loading of the data bus slows down the response time, even though DC specifications are still met. For systems operating with a relatively slow CPU clock frequency, more time is available in which to establish proper logic levels on the bus and therefore higher capacitive loads can be driven (see typical characteristics curves).

At higher CPU clock frequencies time can be extended for I/O reads (and/or writes) by inserting wait states (8080) or using clock extending circuits (6800).

Finally, if time is short and capacitive loading is high, external bus drivers must be used. These can be TRI-STATE buffers (low power Schottky such as the DM74LS240 series is recommended) or special higher drive current products which are designed as bus drivers. High current bipolar bus drivers with PNP inputs are recommended.

### 2.10 Power Supplies

Noise spikes on the  $V_{CC}$  supply line can cause conversion errors as the comparator will respond to this noise. A low inductance tantalum filter capacitor should be used close to the converter  $V_{CC}$  pin and values of 1  $\mu\text{F}$  or greater are recommended. If an unregulated voltage is available in the system, a separate LM340LAZ-5.0, TO-92, 5V voltage regulator for the converter (and other analog circuitry) will greatly reduce digital noise on the  $V_{CC}$  supply.

### 2.11 Wiring and Hook-Up Precautions

Standard digital wire wrap sockets are not satisfactory for breadboarding this A/D converter. Sockets on PC boards can be used and all logic signal wires and leads should be grouped and kept as far away as possible from the analog signal leads. Exposed leads to the analog inputs can cause undesired digital noise and hum pickup, therefore shielded leads may be necessary in many applications.

## Functional Description (Continued)

A single point analog ground that is separate from the logic ground points should be used. The power supply bypass capacitor and the self-clocking capacitor (if used) should both be returned to digital ground. Any  $V_{REF}/2$  bypass capacitors, analog input filter capacitors, or input signal shielding should be returned to the analog ground point. A test for proper grounding is to measure the zero error of the A/D converter. Zero errors in excess of  $\frac{1}{4}$  LSB can usually be traced to improper board layout and wiring (see section 2.5.1 for measuring the zero error).

### 3.0 TESTING THE A/D CONVERTER

There are many degrees of complexity associated with testing an A/D converter. One of the simplest tests is to apply a known analog input voltage to the converter and use LEDs to display the resulting digital output code as shown in Figure 7.

For ease of testing, the  $V_{REF}/2$  (pin 9) should be supplied with 2.560 V<sub>DC</sub> and a  $V_{CC}$  supply voltage of 5.12 V<sub>DC</sub> should be used. This provides an LSB value of 20 mV.

If a full-scale adjustment is to be made, an analog input voltage of 5.090 V<sub>DC</sub> (5.120 -  $\frac{1}{2}$  LSB) should be applied to the  $V_{IN}(+)$  pin with the  $V_{IN}(-)$  pin grounded. The value of the  $V_{REF}/2$  input voltage should then be adjusted until the digital output code is just changing from 1111 1110 to 1111 1111. This value of  $V_{REF}/2$  should then be used for all the tests.

The digital output LED display can be decoded by dividing the 8 bits into 2 hex characters, the 4 most significant (MS) and the 4 least significant (LS). Table I shows the fractional binary equivalent of these two 4-bit groups. By adding the voltages obtained from the "VMS" and "VLS" columns in Table I, the nominal value of the digital display (when

$V_{REF}/2 = 2.560\text{V}$ ) can be determined. For example, for an output LED display of 1011 0110 or B6 (in hex), the voltage values from the table are 3.520 + 0.120 or 3.640 V<sub>DC</sub>. These voltage values represent the center-values of a perfect A/D converter. The effects of quantization error have to be accounted for in the interpretation of the test results.

For a higher speed test system, or to obtain plotted data, a digital-to-analog converter is needed for the test set-up. An accurate 10-bit DAC can serve as the precision voltage source for the A/D. Errors of the A/D under test can be expressed as either analog voltages or differences in 2 digital words.

A basic A/D tester that uses a DAC and provides the error as an analog output voltage is shown in Figure 8. The 2 op amps can be eliminated if a lab DVM with a numerical subtraction feature is available to read the difference voltage, "A-C", directly. The analog input voltage can be supplied by a low frequency ramp generator and an X-Y plotter can be used to provide analog error (Y axis) versus analog input (X axis). The construction details of a tester of this type are provided in the NSC application note AN-179, "Analog-to-Digital Converter Testing".

For operation with a microprocessor or a computer-based test system, it is more convenient to present the errors digitally. This can be done with the circuit of Figure 9, where the output code transitions can be detected as the 10-bit DAC is incremented. This provides  $\frac{1}{4}$  LSB steps for the 8-bit A/D under test. If the results of this test are automatically plotted with the analog input on the X axis and the error (in LSB's) as the Y axis, a useful transfer function of the A/D under test results. For acceptance testing, the plot is not necessary and the testing speed can be increased by establishing internal limits on the allowed error for each code.

### 4.0 MICROPROCESSOR INTERFACING

To discuss the interface with 8080A and 6800 microprocessors, a common sample subroutine structure is used. The microprocessor starts the A/D, reads and stores the results of 16 successive conversions, then returns to the user's program. The 16 data bytes are stored in 16 successive memory locations. All Data and Addresses will be given in hexadecimal form. Software and hardware details are provided separately for each type of microprocessor.

#### 4.1 Interfacing 8080 Microprocessor Derivatives (8048, 8085)

This converter has been designed to directly interface with derivatives of the 8080 microprocessor. The A/D can be mapped into memory space (using standard memory address decoding for CS and the MEMR and MEMW strobes) or it can be controlled as an I/O device by using the IOR and IOW strobes and decoding the address bits A0 → A7 (or address bits A8 → A15 as they will contain the same 8-bit address information) to obtain the CS input. Using the I/O space provides 256 additional addresses and may allow a simpler 8-bit address decoder but the data can only be input to the accumulator. To make use of the additional memory reference instructions, the A/D should be mapped into memory space. An example of an A/D in I/O space is shown in Figure 10.

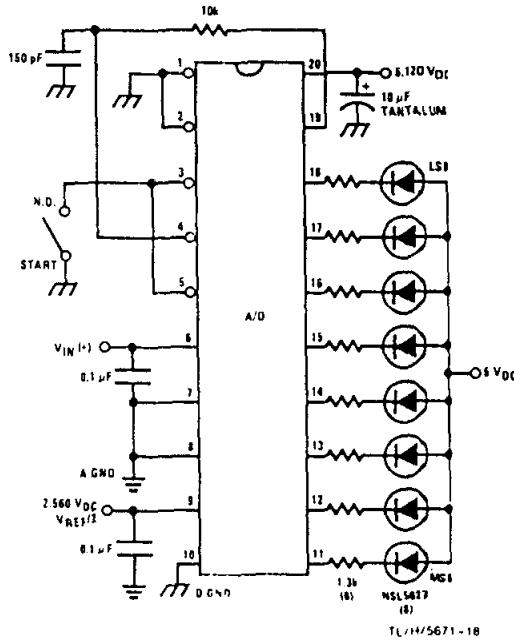


FIGURE 7. Basic A/D Tester

## Functional Description (Continued)

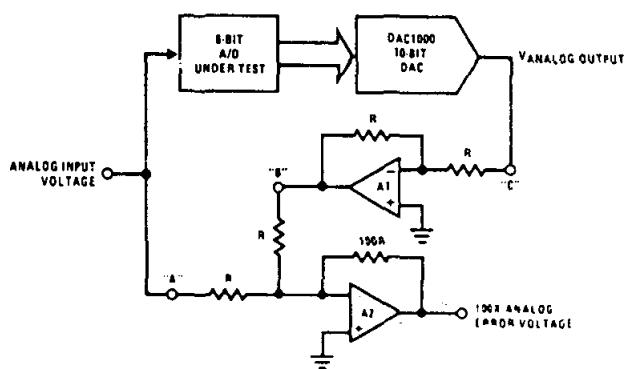


FIGURE 8. A/D Tester with Analog Error Output

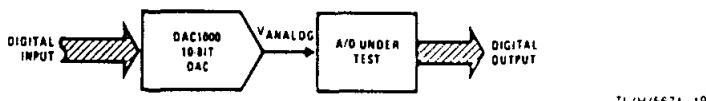


FIGURE 9. Basic "Digital" A/D Tester

TABLE I. DECODING THE DIGITAL OUTPUT LEDs

HEX	BINARY	FRACTIONAL BINARY VALUE FOR		OUTPUT VOLTAGE CENTER VALUES WITH $V_{REF}/2 = 2,560 \text{ V}_{DC}$	
		MS GROUP	LS GROUP	VMS GROUP*	VLS GROUP*
F	1 1 1 1		15/16	15/256	4.800
E	1 1 1 0		7/8	7/128	4.480
D	1 1 0 1		13/16	13/256	4.160
C	1 1 0 0	3/4	3/64	3/256	3.840
B	1 0 1 1		11/16	11/256	3.520
A	1 0 1 0		5/8	5/128	3.200
9	1 0 0 1		9/16	9/256	2.880
8	1 0 0 0	1/2	1/32	1/256	2.560
7	0 1 1 1		7/16	7/256	2.240
6	0 1 1 0		3/8	3/128	1.920
5	0 1 0 1		5/16	2/256	1.600
4	0 1 0 0	1/4	1/64	1/280	0.080
3	0 0 1 1		3/16	3/256	0.960
2	0 0 1 0		1/8	1/128	0.640
1	0 0 0 1		1/16	1/256	0.320
0	0 0 0 0			0	0

## DAFTAR RIWAYAT HIDUP



Nama : Handoko Purnomo

NIRM: 96.7.003.31073.44906

Tempat, Tanggal. Lahir : Pasuruan,

30 Desember 1977

Agama : Katolik

Alamat: Wonorejo III /43B, Surabaya

### Riwayat Pendidikan :

- SD Pancasila Pasuruan tahun 1984-1990
- SMPK Pecinta Damai, Surabaya tahun 1990-1993
- SMAK Santa Agnes, Surabaya tahun 1993-1996
- Universitas Katolik Widya Mandala Fakultas Teknik Jurusan Teknik Elektro  
tahun 1996